

Notice of References Cited

Application/Control No.

10/572,589

Applicant(s)/Patent Under

Reexamination

YAMAUCHI ET AL.

Examiner

SHIN-HON CHEN

Art Unit

2431

Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2007/0100755	05-2007	Kragt et al.	705/051
*	B US-7,093,296	08-2006	Nusser et al.	726/26
*	C US-2002/0120577	08-2002	Hans et al.	705/59
*	D US-2005/0177516	08-2005	Vandewater et al.	705/057
*	E US-2003/0078853	04-2003	Peinado et al.	705/26
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.